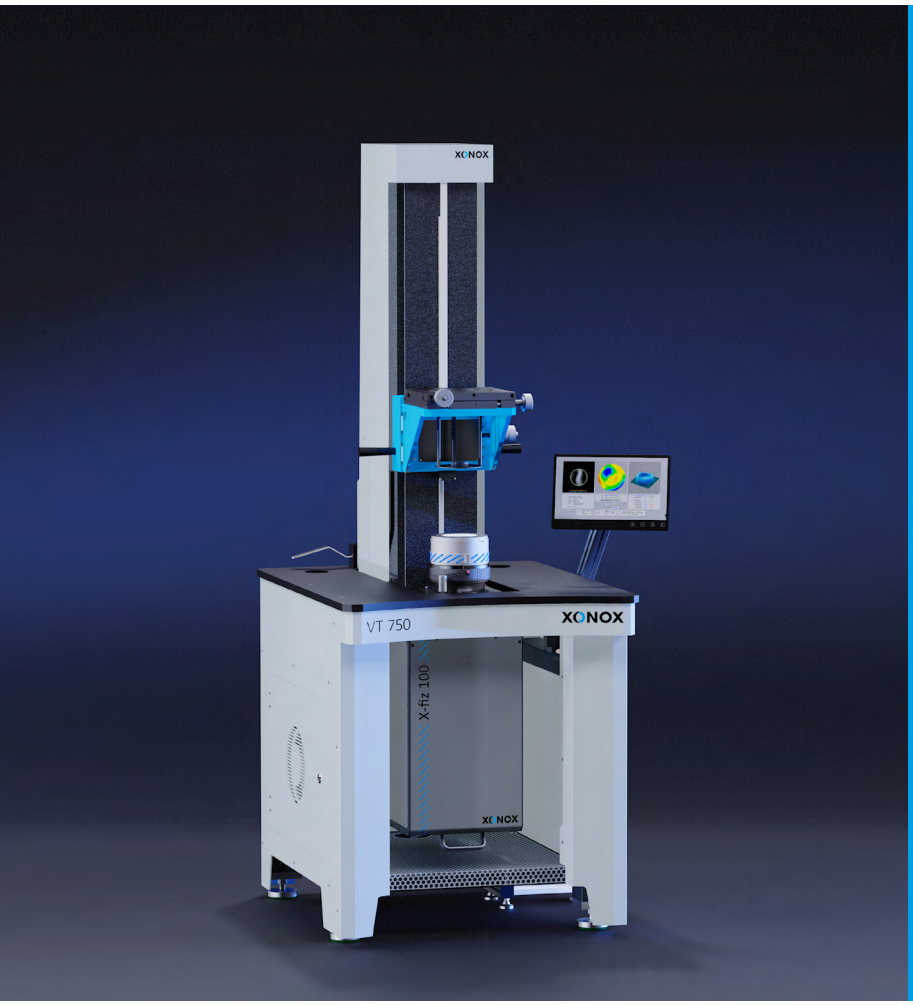
VT 750



VERTICAL INTERFEROMETER SYSTEM

_ precision interferometer tower for production-, quality in-spection- and metrology lab environments

_ large measuring range for radii up to 800mm

_ natural granite column with extremely flat and precise guiding surfaces provide for ease of use and very accurate measurement of radius of curvature on optical components

_ highly precise and accurate linear scale with exceptional resolution, directly interfaced to fringe analysis software

_ measurement table is balanced and guided on air bearing slide for quick, easy and accurate setup and movement

_ small foot print and exceptional value combined with high accuracy and and rigit, maitenance free design

_ robust vibration damping system, prefect for use in industrial production environments

_ XONOX X-fiz 100 (4" & 5.2") or X-fiz 150 (6") high performance Fizeau interferometer with electronic control of zoom, focus and contrast/saturation

_ innovative, powerful and user friendly fringe analysis system X-fringe PS2 with different smart and intelligent modes to suit various applications

_ system can be equipped either with PC table, 2 screens, mouse and keyboard or with touch panel for optimized operation and minimized space requirement in production environment

_ additionally available in a "tower only" version „B" for integrating existing or 3rd party interferometer units

WORKING RANGE	min. 750mm travel (800mm linear scale range), up to 200mm test diameter (depending on used TS and partholder) + micrometer fine adjustment for easy and precise setting of catseye and confocal position Distance between column and optical axis = 145mm allows for lodaing workpieces up to Ø290mm - adaptation diameter for lens holders = Ø152.4mm				
VERSIONS	_ **VT750 PS2** with XONOX **X-fiz 100 (4" & 5,2") / X-fiz 150 (6")** with eletronic zoom, focus and contrast (saturation) controll and 5MPX CMOS camera. Phase shifting fringe analysis system XONOX **„X-fringe PS2"** and piezo phase shifter XONOX **„X-phase PMR"** _ **VT750 B** „tower only" version for integrating existing interferometer units. Optionally with XONOX fringe analysis system X-fringe PS2 and X-phase PMR phase shifter.				
MEASURING AXIS	counterbalanced, air bearing guided axis with smooth, „zero weight" manual movement via handle (standard). Optionally electric driven via joystick (optional). Wear out and maintenance free design.				
MEASURING SYSTEM	incremental high precision linear measuring system with PC interface and temperature expansion compensation function (standard) / alternatively with „in axis" distance measuring laser interferometer (LDM)with compensation unit for temperature, humidity and air preasure (optional)				
MEASURING ACCURACY	linear scale: up to +/- 1.5µm per 1000mm @ 20°C, up to 0.1µm resolution (standard 0.5µm) optionally with callibration and error compensation (on request) LDM: +/- 0.2 per 1000mm including automatic environmental compensation. Resolution 0.1µm				
VIBRATION ISOLATION	Equipped with 4 adjustable passive vibration dampeners (standard). Optionally with active, piezo controlled vibration dampening system with 4 piezo blocks and fully automatic vibration dampening (optional)				
DIMENSIONS (WxDxH)	800 x 900 x 2100 mm when using touch screen and integrated PC for fringe analysis (additional space required if separate PC is used for fringe analysis, XONOX PC-table optionally available)				
WEIGHT	approx. 750kg	**CONNECTIONS**	110-240 V / 50-60 Hz, compressed air: 6 bar	**COLOR**	Light grey RAL 7035

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iQC READY

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